

PATENT APPLICATION

IN THE U.S. PATENT AND TRADEMARK OFFICE

September 20, 2006

Applicant(s) : Yoshihide KIYOSAWA

For : WAVE GEAR DEVICE

Serial No. : 10/587 004

Group: Unknown

Confirmation No.: 2915

Filed : July 20, 2006

Examiner: Unknown

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Atty. Docket No.: 5725.P0023US

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is Form PTO-1449 which cites the U.S. equivalent to the Japanese reference SHO50-12066 cited in applicant's Information Disclosure Statement at the time of filing this application. Copies of cited U.S. references are not submitted in accordance with 37 CFR 1.98(a).

Further consideration is respectfully solicited.

Respectfully submitted,


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INFORMATION
DISCLOSURE
CITATION

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U.S. PATENT DOCUMENTS

| Examiner Initials* | Cite No. | Document Number - Kind Code | Publication Date MM-DD-YYYY | Name of Patentee or Applicant |
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FOREIGN PATENT DOCUMENTS

| Examiner Initials* | Cite No. | Country Code - Document Number - Kind Code | Publication Date MM-DD-YYYY | Name of Patentee or Applicant | Trans. |
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NON PATENT LITERATURE DOCUMENTS

| Examiner Initials* | Cite No. | (Include Author, Title, Date, Pages, Etc.) |
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